



8th International Workshop on Mechanisms of Vacuum Arcs

Study on phenomenon of high energy protons bombarding electrode

Ao Xu, Dazhi Jin, Yajun Wang, Xiaohua Tan 2019.09



2 Simulation model

3 Simulation results and analysis

4 conclusion

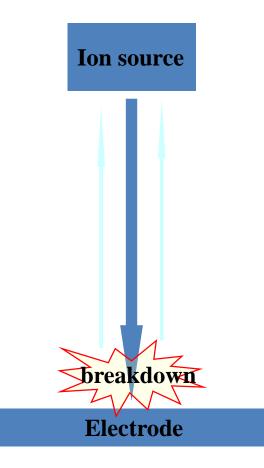


When ion accelerators or film deposition instruments are operating, it is possible to induce breakdown by ion beam bombarding electrodes.

But the operating voltage is not enough to induced breakdown in these instruments without the ion source working.

Therefore, it is unambiguously that the interaction between high energy ions and electrode can obviously decrease the breakdown voltage in vacuum gaps.

In order to illuminate this physical mechanism, the proton beam bombarding electrode under high voltage condition is selected as a typical physical model.





2 Simulation model

3 Simulation results and analysis

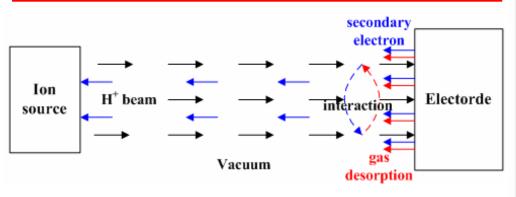
4 conclusion



Simulation setting

Туре	setting
Code	PIC-DSMC
Dimensionality	1D
Electrode	Stainless steel
Background	1×10 ⁻⁵ Pa, H ₂
Ion beam	H+
Adsorb gas	H ₂
Sputter	non
Particle species	e, H, H ⁺ , H ^{2s} , H ₂ , H ₂ ⁺
Interval	5mm
Voltage	-50kV

The ion source only emit H⁺, the emission flux of H+ is 2×10^{23} m⁻²s⁻¹ and the initial velocity is a local Maxwell distribution at temperature of 0.5eV and the mean velocity of 20000m/s.



Particles bombard electrode

Interactions

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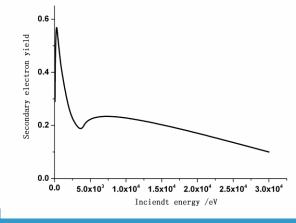
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Index	Туре	Index	Туре
1	$e+e \rightarrow e+e$	13	$\begin{array}{c} e{+}H_2 \rightarrow e{+}H_2^{\text{L-bnd}} \rightarrow \\ e{+}H_2 \end{array}$
2	$e{+}H \rightarrow 2e{+}H^{+}$	14	$\begin{array}{c} e{+}H_2 \rightarrow e{+}H_2^{W{-}bnd} \rightarrow \\ e{+}H_2 \end{array}$
3	$e{+}H^{2s}{\rightarrow}e{+}H^{+}{+}e$	15	$\rm e{+}H_2 \rightarrow \rm e{+}H{+}H^{2s}$
4	$H^++H_2 \rightarrow H^++H^++H^++2e$	16	$\begin{array}{c} \mathbf{e} + \mathbf{H}_2 \rightarrow \mathbf{e} + \mathbf{H}_2 ^{\mathbf{J} = 0 - 2} \rightarrow \\ \mathbf{e} + \mathbf{H}_2 \end{array}$
5	$\rm H^+\!+\!H_2 \!\rightarrow \rm H^+\!+\!H^{2s}\!+\!H$	17	$\begin{array}{c} \mathbf{e} + \mathbf{H}_2 \rightarrow \mathbf{e} + \mathbf{H}_2^{\mathbf{J} = \mathbf{l} - 3} \rightarrow \\ \mathbf{e} + \mathbf{H}_2 \end{array}$
6	${\rm H^+\!\!+\!H} ightarrow {\rm H^+\!\!+\!H^+\!\!+\!e}$	18	$\rm e{+}H_2 \rightarrow 2\rm e{+}H{+}H^{+}$
7	$H^++H_2 \rightarrow H^++H_2^++e$	19	$e+H_2 \rightarrow H+H+e$
8	$H^+ + H_2 \rightarrow H_2^+ + H$	20	$\begin{array}{c} e{+}H_2 \rightarrow H^{v1,v2,v3}{+}e \rightarrow \\ H_2{+}e \end{array}$
9	$\mathrm{H^{+}\!\!+\!H} \to \mathrm{H}\!\!+\!\mathrm{H^{+}}$	21	$\mathbf{H_2^+\!\!+\!\!H_2\!\rightarrow H^+\!\!+\!\!H\!\!+\!\!H_2}$
10	$e{+}H_2 {\rightarrow} H_2{+}e$	22	${\rm H_2^+\!\!+\!H} \mathop{\rightarrow} {\rm H^+\!\!+\!H_2}$
11	$e{+}H_2 \rightarrow H_2^+{+}e{+}e$	23	$e{+}H_2^+{\rightarrow}2H$
12	$\begin{array}{c} e{+}H_{2} \rightarrow e{+}H{+}H^{L\text{-}alp} \rightarrow \\ e{+}H{+}H \end{array}$	24	$e{+}H_2^+{\rightarrow} e{+}H^+{+}H$

Туре	setting	
H, H^{2s}, H_2	Random reflected (coefficient is 1)	
H+	Secondary electron generation (yield is 2.5)	
	Adsorbed gas, H ₂ (rate are 1000, 10000, 100000)	
$\mathbf{H_{2}^{+}}$	1.5	

Secondary electron generation by bombardment of electrons





The present simulations could adopt the same grid and time step which are demanded in PIC simulation, namely, grid equal to 0.2µm and time step equal to 10⁻¹⁵ s.
 If the conduction current in gaps abruptly increase more than 100 times, it is considered as breakdown in the gaps. And if the conduction current has no increase for a long time, the simulation is interrupted factitiously.



2 Simulation model

3 Simulation results and analysis

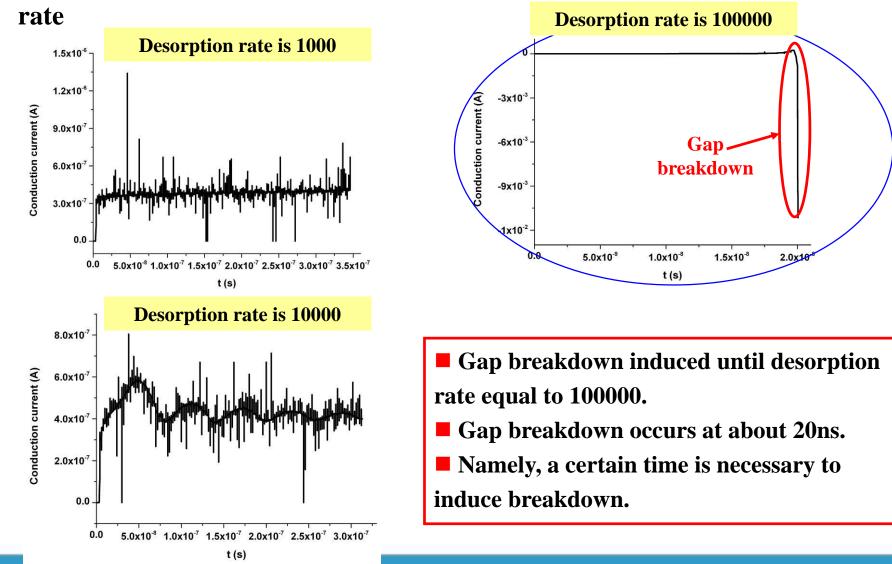
4 Conclusion

Simulation results and analysis

3.1 Conduction current for different desorption

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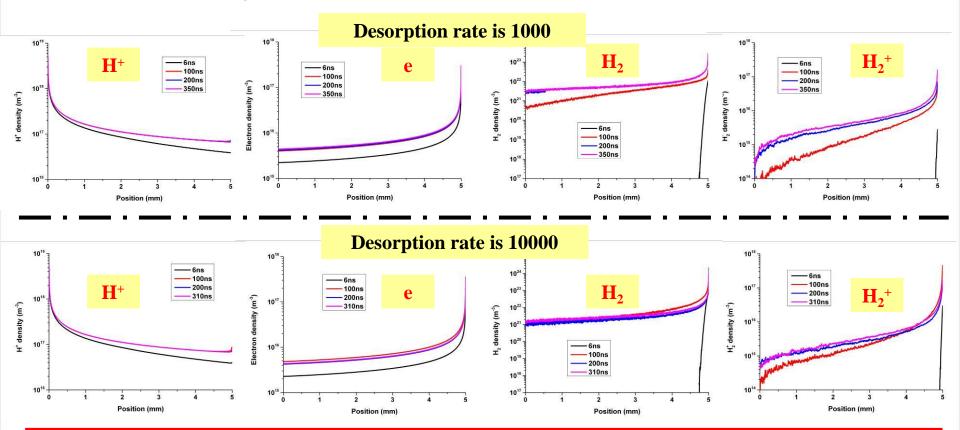
3.2 Particles density distribution evolution (for breakdown not occurs)

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Simulation results and analysis

■ H₂ uninterrupted generated by bombardment of H⁺, but it could not induce breakdown until the gas fulfill the gap;

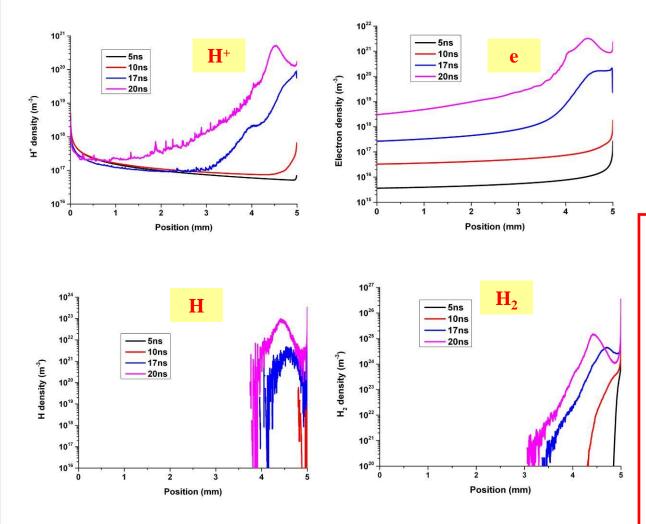
With the desorption rate increase, H_2^+ density a few increase, but electron density hardly increase.

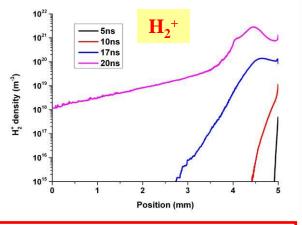
3.3 Particles density distribution evolution (for breakdown occurs)

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Simulation results and analysis

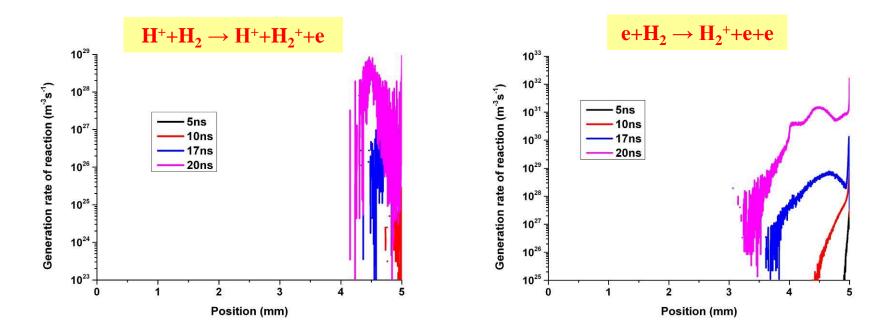
■ When breakdown occurs, H₂ not fulfill the gap, but the density reach 10²⁵m⁻³ near the electrode

When breakdown occurs, H⁺ density obviously increase, it is related to abundant H appears.

Electrons avalanche in local high density gas near electrode is the main reason to induce gap breakdown.



3.4 Generation rate of different reactions



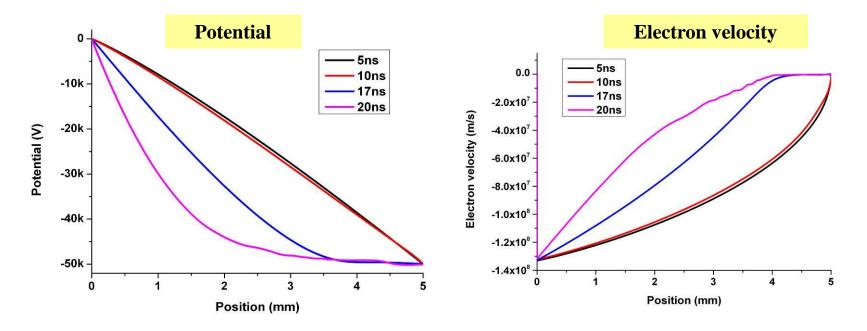
■ It is evident that electrons ionization H₂ is much more than H⁺ ionization H₂ to produce electrons.

■ The "initial" electrons to ionization H₂ actually are the secondary electrons generated by H⁺ bombarding electrode.



Simulation results and analysis

3.5 Potential distribution and electron velocity distribution



The appearance of high density electrons and ions lead to the form of plasma sheath near the high voltage electrode.

Electrons velocity decrease evidently while plasma sheath forms near the high voltage electrode. And it lead to electrons are more possible to interact with local high density H₂ which desorption form the high voltage electrode.



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■ The critical value of local desorption gas density to induced breakdown is 10²⁵m⁻³ obtained by simulations.

Secondary electrons generation at the high voltage electrode by the bombardment of protons and electrons ionization desorption gas near the high voltage electrode are the key factors to induce breakdown.

The form of sheath near the high voltage electrode is available to electrons avalanche.



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Thanks for your attention!